

AUTOMOTIVE CURRENT TRANSDUCER OPEN LOOP TECHNOLOGY

HAH3DR 1500-S07/SP7



Introduction

The HAH3DR-S07 family is a tri-phase transducer for DC, AC, or pulsed currents measurement in automotive applications. It offers a galvanic separation between the primary circuit (high power) and the secondary circuit (electronic circuit).

Features

- Open Loop transducer using the Hall effect sensor
- Low voltage application
- Unipolar +5 V DC power supply
- Primary current measuring range up to ± 1500 A
- Maximum RMS primary admissible current: limited by the busbar, the magnetic core or ASIC $T < +125$ °C
- Operating temperature range: -40 °C $< T < +125$ °C
- Output voltage fully ratiometric (in sensitivity and offset)
- All in one tri-phase transducer
- Perfect fit to Infineon 'HybridPACK™' drive IGBT.

Special Features

- Special mounting interface
- Enlarged aperture compatible with the busbar 1.0 mm and 1.5 mm thickness.

Advantages

- Excellent accuracy
- Very good linearity
- Very low thermal offset drift
- Very low thermal sensitivity drift
- High frequency bandwidth
- No insertion losses
- Very fast delay time.

Automotive applications

- Starter Generators
- Inverters
- HEV applications
- EV applications
- DC / DC converter.

Principle of HAH3DR S07 family

The open loop transducers uses a Hall effect integrated circuit. The magnetic flux density B , contributing to the rise of the Hall voltage, is generated by the primary current I_p to be measured. The current to be measured I_p is supplied by a current source i.e. battery or generator (Figure 1). Within the linear region of the hysteresis cycle, B is proportional to:

$$B(I_p) = a \times I_p$$

The Hall voltage is thus expressed by:

$$U_{Hall} = (c_{Hall} / d) \times I_{Hall} \times a \times I_p$$

Except for I_p , all terms of this equation are constant. Therefore:

$$U_{Hall} = b \times I_p$$

a constant

b constant

c_{Hall} Hall coefficient

d thickness of the Hall plate

I_{Hall} current across the Hall plates

The measurement signal U_{Hall} amplified to supply the user output voltage or current.

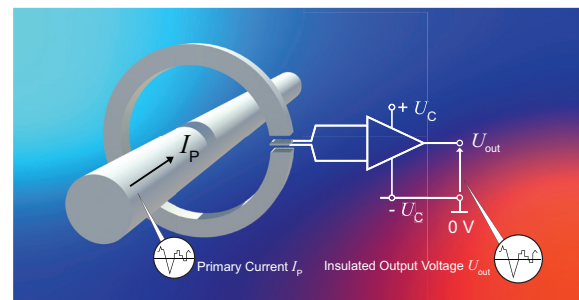
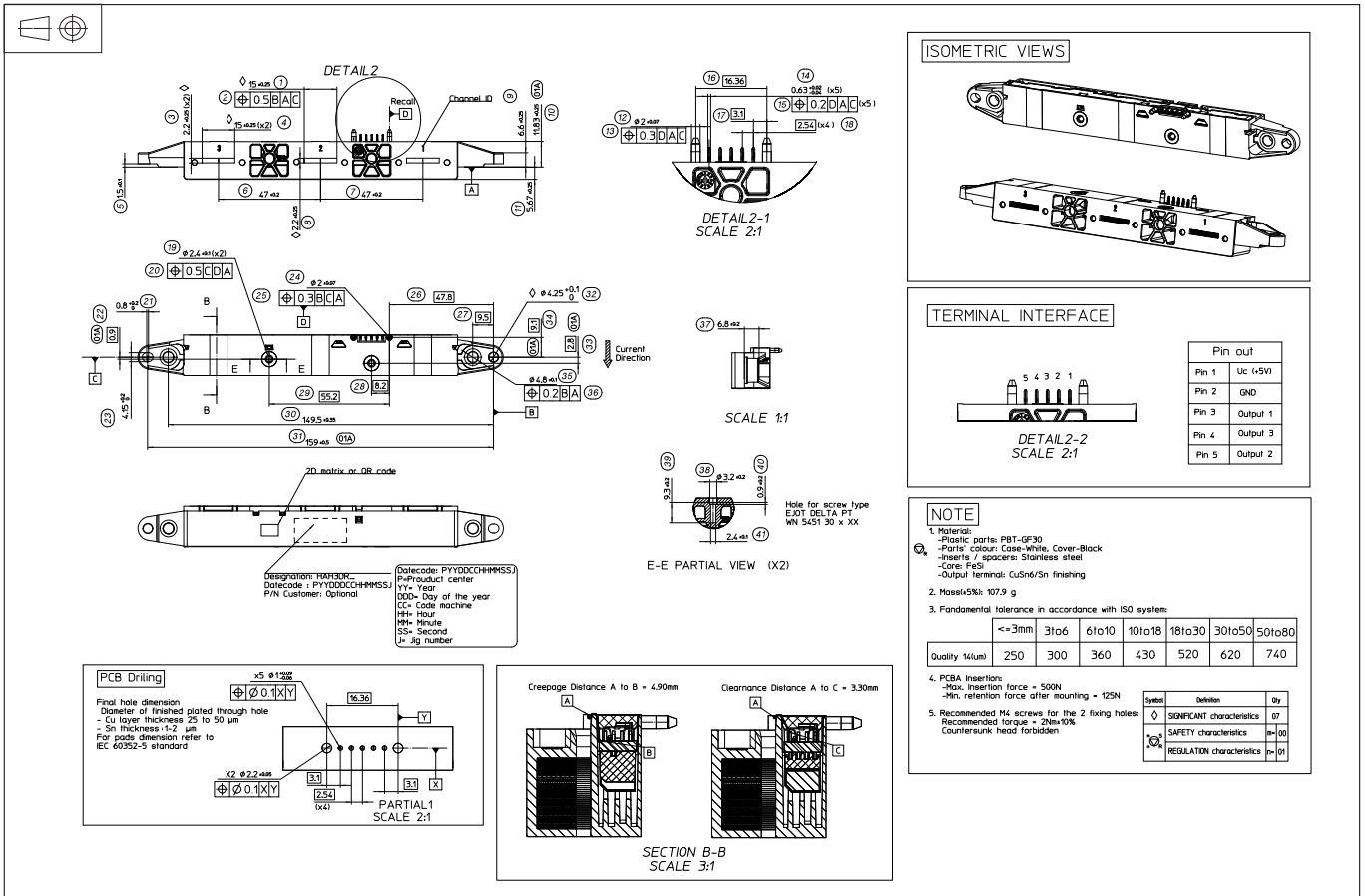


Fig. 1: Principle of the open loop transducer.

Dimensions (in mm)



Mechanical characteristics

- Materials: PBT-GF30
- Pins: CuSn6, Sn Plating
- Mass: 108 ± 5 % g

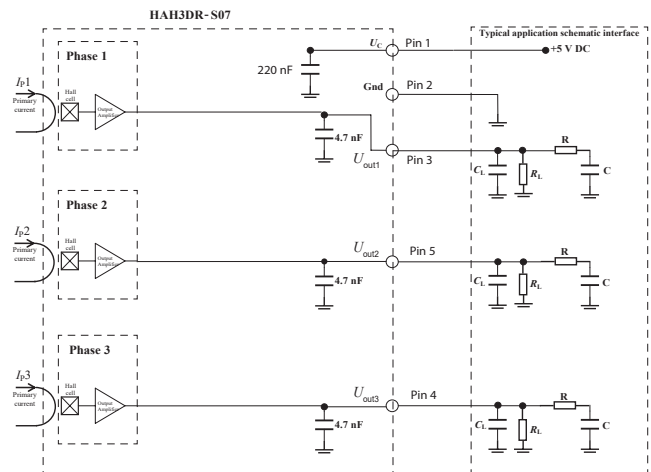
Mounting recommendation

- Positioning refers to drawing
- Secondary connection: Pressfit (see dimensions)
 - Max. insertion force for 5 press fit pins = 500 N
 - Min. retention force after mounting = 125 N
- M4 screws
 - Recommended torque 2 N·m ± 10 %
- DELTA PT ® WN 5451 30, torque = 0.8 N·m ± 5 %

Remark

$U_{out} > U_0$ when I_p flows in the positive direction (see arrow on drawing).

System architecture (example)



$C_L < 2.2$ nF EMC protection (optional)
 RC Low pass filter (optional).

On board diagnostic

$R_L > 10$ kΩ. Resistor for signal line diagnostic (optional).

Absolute ratings (not operating)

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
Maximum supply voltage	U_{Cmax}	V	-0.5		8	Continuous not operating
					6.5	Exceeding this voltage may temporarily reconfigure the circuit until the next power on
Ambient storage temperature	T_{Ast}	°C	-40		125	
Electrostatic discharge voltage	U_{ESD}	kV			8	
RMS voltage for AC insulation test	U_d	kV			2.5	50 Hz, 1 min, IEC 60664 part1
Creepage distance	d_{Cp}	mm	4.9			
Clearance	d_{Cl}	mm	3.3			
Comparative tracking index	CTI		PLC3			
Insulation resistance	R_{INS}	MΩ	500			500 V DC, ISO 16750

Operating characteristics

All characteristics noted under conditions $-1500 A \leq I_p \leq 1500 A$, $4.75 V \leq U_c \leq 5.25 V$, $-40 °C \leq T_A \leq 125 °C$, unless otherwise noted.

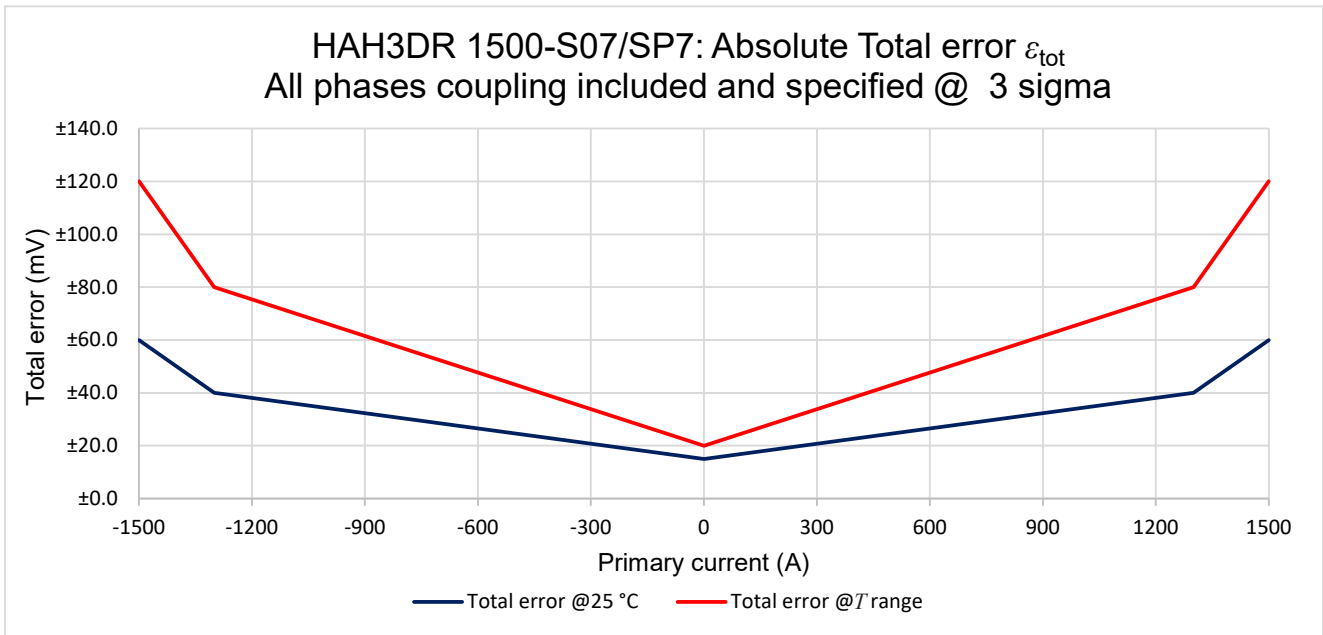
Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
Electrical Data						
Primary current, measuring range	I_{PM}	A	-1500		1500	
Supply voltage ¹⁾	U_C	V	4.75	5	5.25	
Ambient operating temperature	T_A	°C	-40		125	
Output voltage (Analog)	U_{out}	V	$U_{out} = (U_C/5) \times (U_O + S \times I_p)$			@ $T_A = 25 °C$
Sensitivity	S	mV/A		1.33		
Offset voltage	U_O	V		2.5		
Current consumption	I_C	mA		45	60	@ $U_C = 5 V$
Load resistance	R_L	KΩ	10			
Output internal resistance	R_{out}	Ω		1	10	
Performance Data						
Ratiometricity error	ϵ_r	%		±0.5		
Sensitivity error	ϵ_S	%		±0.6		@ $T_A = 25 °C$, @ $U_C = 5 V$
Electrical offset voltage	U_{OE}	mV		±2		@ $T_A = 25 °C$, @ $U_C = 5 V$
Magnetic offset voltage	U_{OM}	mV		±1		@ $T_A = 25 °C$, @ $U_C = 5 V$, after $\pm I_{PM}$
Average temperature coefficient of U_{OE}	TCU_{OEAV}	mV/°C		±0.05		
Average temperature coefficient of S	TCS_{AV}	%/°C		±0.03		
Linearity error	ϵ_L	%	-1		1	% of linear range $I_p < 1300 A $
Delay time to 90 % to the final output value for I_{PN} step	t_{D90}	μs		2	6	$di/dt = 100 A / \mu s$
Frequency bandwidth ²⁾	BW	kHz	40			@ -3 dB
Phase shift	$\Delta\phi$	°	-4			@ DC to 1 kHz

Notes: ¹⁾ The output voltage U_{out} is fully ratiometric. The offset and sensitivity are dependent on the supply voltage U_c relative to the following formula:

$$I_p = \left(\frac{5}{U_C} \times U_{out} - U_O \right) \times \frac{1}{S} \text{ with } S \text{ in (V/A)}$$

²⁾ Primary current frequencies must be limited in order to avoid excessive heating of the busbar, magnetic core and the ASIC (see feature paragraph in page 1).

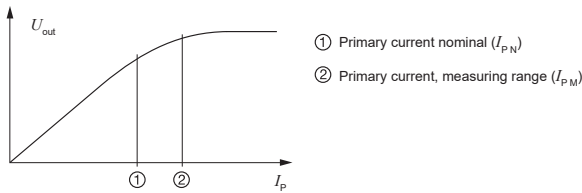
Total error



Primary current (A)	Total error @ 25 °C			Total error @ T range		
	(mV)	(A)	(%)	(mV)	(A)	(%)
-1500	±60	±45	3.0 %	±120	±90	6.0 %
-1300	±40	±30	2.0 %	±80	±60	4.0 %
0	±15	±11.25	0.8 %	±20	±15	1.0 %
1300	±40	±30	2.0 %	±80	±60	4.0 %
1500	±60	±45	3.0 %	±120	±90	6.0 %

PERFORMANCES PARAMETERS DEFINITIONS

Primary current definition:



Definition of typical, minimum and maximum values:

Minimum and maximum values for specified limiting and safety conditions have to be understood as such as values shown in “typical” graphs. On the other hand, measured values are part of a statistical distribution that can be specified by an interval with upper and lower limits and a probability for measured values to lie within this interval. Unless otherwise stated (e.g. “100 % tested”), the LEM definition for such intervals designated with “min” and “max” is that the probability for values of samples to lie in this interval is 99.73 %. For a normal (Gaussian) distribution, this corresponds to an interval between -3 sigma and $+3$ sigma. If “typical” values are not obviously mean or average values, those values are defined to delimit intervals with a probability of 68.27 %, corresponding to an interval between $-\text{sigma}$ and $+\text{sigma}$ for a normal distribution. Typical, minimum and maximum values are determined during the initial characterization of a product.

Output noise voltage:

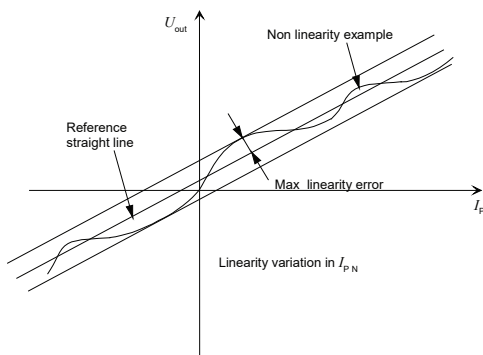
The output voltage noise is the result of the noise floor of the Hall elements and the linear amplifier.

Magnetic offset:

The magnetic offset is the consequence of an any current on the primary side. It's defined after a stated excursion of primary current.

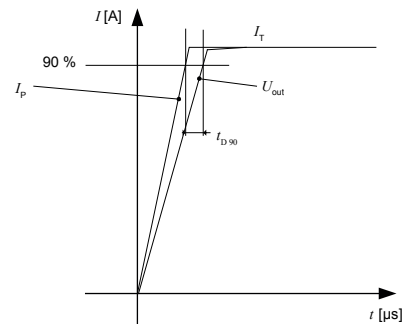
Linearity:

The maximum positive or negative discrepancy with a reference straight line $U_{out} = f(I_p)$.
 Unit: linearity (%) expressed with full scale of I_{pN} .



Delay time t_{D90} :

The time between the primary current signal (I_{pN}) and the output signal reach at 90 % of its final value.



Sensitivity:

The transducer's sensitivity S is the slope of the straight line

$U_{out} = f(I_p)$, it must establish the relation:

$$U_{out}(I_p) = U_c/5 (S \times I_p + U_o)$$

Offset with temperature:

The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25 °C.

The offset variation I_{OT} is a maximum variation the offset in the temperature range:

$$I_{OT} = I_{OE \max} - I_{OE \min}$$

The offset drift $TCI_{OEA V}$ is the I_{OT} value divided by the temperature range.

Sensitivity with temperature:

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25 °C.

The sensitivity variation S_T is the maximum variation (in ppm or %) of the sensitivity in the temperature range:
 $S_T = (\text{Sensitivity max} - \text{Sensitivity min}) / \text{Sensitivity at } 25 \text{ } ^\circ\text{C}$.

The sensitivity drift TCS_{AV} is the S_T value divided by the temperature range. Deeper and detailed info available is our LEM technical sales offices (www.lem.com).

Offset voltage @ $I_p = 0$ A:

The offset voltage is the output voltage when the primary current is zero. The ideal value of U_o is $U_c/2$. So, the difference of $U_o - U_c/2$ is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis. Deeper and detailed info available is our LEM technical sales offices (www.lem.com).

Environmental test specifications:

Refer to LEM GROUP test plan laboratory CO.11.11.515.0 with “Tracking_Test Plan_Auto” sheet.

Verification Test Specification

Name	Standard	Condition
ELECTRICAL TESTS		
Frequency bandwidth	LEM 98.20.00.538.0	30 Hz to 100 kHz; @ 20 A peak; ≥40 kHz @ -3 dB
Phase delay	LEM 98.20.00.538.0	$U_C = 5\text{ V}$, 30 Hz to 100 kHz; At 20 A peak; Phase delay ≥ -4° @ 1 kHz
Delay time; di/dt	LEM 98.20.00.545.0	100 A/μs I_P pulse = 1100 A; t_{D90} of $I_{PN} \leq 6\ \mu\text{s}$
di/dt	LEM 98.20.00.545.0	Slope: 5 kV/μs $U = 1000\text{ V}$
ENVIRONMENTAL TESTS		
Ageing 85 °C /85 % RH	JESD 22-A101 (03/2009)	$T^\circ\text{C} = 85^\circ\text{C}$; RH = 85 %; Duration = 1000 h $U_C = 5\text{ V}$; $I_P = 0\text{ A}$; Monitoring each 60 min
Low temperature storage	ISO 16750-4 § 5.1.1.2 (04/2010)	$T^\circ\text{C} = -40^\circ\text{C}$, Duration = 24 h; $U_C = 5\text{ V}$ Monitoring: 2 times per hour
High temperature storage	ISO 16750-4 § 5.1.2.2 (04/2010)	$T^\circ\text{C} = 125^\circ\text{C}$, Duration = 96 h; $U_C = 5\text{ V}$ Monitoring 2 times per hour
Humidity heat, cyclic test: Test 2 Composite temperature/humidity cyclic test	ISO 16750-4 § 5.6.2.3 (04/2010)	$T^\circ\text{C} = -10^\circ\text{C}/+65^\circ\text{C}$, Humidity = 93 % Duration = 240 h; (10 cycles)
Thermal shock	ISO 16750-4 § 5.3.2 (04/2010)	$T^\circ\text{C} = -40^\circ\text{C}$ & 125°C , Duration = 500 cycles; 40 mins/40 mins $U_C = \text{NO power supply}$ (\equiv unconnected) and No wiring harness
Sinus Vibration	ISO 16750-3 § 4.1.2.2.2 (12/2012)	Monitoring U_C and U_{out} is mandatory, Temperature -40/125 °C, 22 H/axis, 100 Hz to 440 Hz, Sweep: ≤ 0.5 oct/min ;
Random Vibration	ISO 16750-3 § 4.1.2.2.3 (12/2012)	Monitoring U_C and U_{out} is mandatory, Temperature -40/125 °C 10 to 2000 Hz 10 G (RMS), 22 H/axis
Mechanical Shocks	IEC 60068-2-29 IEC 60068-2-27	Pothole: Pulse shape: half sine, peak 25 G, 20 ms; 400 shocks per direction (total 2400), Power on with U_C and U_{out} monitoring Collision: Pulse shape: half sine, peak 50 G, 11 ms; 6 shocks per direction (total 36), Power off
Free Fall	ISO 16750-3 § 4.3 (12/2012)	Height = 1 m on Concrete floor 3 axes; 2 directions by axis; 1 sample by axis
INSULATION TESTS		
Dielectric withstand voltage	ISO 16750-2 § 4.11 (11/2012)	2.5 kV test voltage; time = 60 s; No dielectric breakdown; no flash-over; functional after test
Insulation test	ISO 16750-2 § 4.12 (11/2012)	500 V DC time = 60 s $R_{INS} \geq 500\text{ M}\Omega$ Min
EMC TESTS		
Immunity to Electrostatic Discharges (Handling of devices)	ISO 10605 (07/2008)	Contact discharges: ±4 kV, Air discharges: ±8 kV $U_C = \text{NO power supply}$, Criteria B
Immunity to Radiated disturbances (ALSE)	ISO11452-2 (2019)	Power supply: 5 V $f = 200\text{ MHz}$ to 2000 MHz Criteria : A Criteria A acceptance @ 5 %
Immunity to Conducted disturbances (BCI)	ISO 11452-4 (12/2011)	Level = see Annex E Fig. & Table E.1 $f = 1\text{ MHz}$ to 400 MHz Criteria A acceptance @ 5 %
Emission Radiated (ALSE)	CISPR 25 § 6.5 (2016)	Table 7, Class 5 by default $f = 150\text{ kHz}$ to 2.5 GHz

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